

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Alistair C.H. Rowe, et al.

Examiner: Unassigned

Serial No.: Unassigned

Group Art Unit: Unassigned

Filed: Herewith

Docket: 16791 (03006)

For: Extraordinary Piezoconductance
in Inhomogeneous Semiconductors

Dated: July 24, 2003

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with 37 C.F.R. §§ 1.97 and 1.98, it is requested that the following references, which are also listed on the attached Form PTO-1449, be made of record in the above-identified case.

1. US Patent No.: 5,663,507, dated September 2, 1997, issued to Robert M. Westervelt, et al.;
2. T. Zhou, et al.; "Extraordinary magnetoresistance in externally shunted van der Pauw plates"; Applied Physics Letters; Vol. 78; No. 5; pp. 667-69; (2001);
3. S.A. Solin, et al.; "Nonmagnetic semiconductors as read-head sensors for ultra-high-density magnetic recording"; Applied Physics Letters; Vol. 80; No. 21; pp. 4012-14; (2002);

CERTIFICATE OF MAILING BY "EXPRESS MAIL"

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I hereby certify that this correspondence is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 C.F.R. § 1.10 on the date indicated above and is addressed to the Commissioner for Patents, Box 1450, Alexandria, VA 22313-1450 on July 24, 2003.

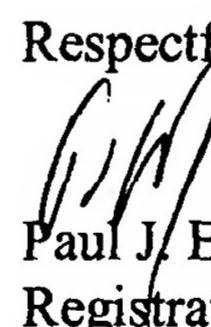
Dated: July 24, 2003


Paul J. Esatto, Jr., Esq.

4. A.C.H. Rowe, et al.; "A uniaxial tensile stress apparatus for temperature-dependent magnetotransport and optical studies of thin films"; Review of Scientific Instruments; Vol. 73; No. 12; pp. 4270-76; (2002)
5. S.A. Solin, et al.; "Enhanced Room-Temperature Geometric Magnetoresistance in Inhomogeneous Narrow-Gap Semiconductors"; Science; Vol. 289; pp. 1530-32; (2000)
6. C.A. Mead, et al.; "Fermi Level Position at Metal-Semiconductor Interfaces"; Physical Review; Vol. 134; No. 3A; pp. A713-16; (1964);
7. G. Margaritondo; "Interface states at semiconductor junctions"; Rep. Prog. Phys.; Vol. 62; pp. 7650-808; (1999)
8. C.S. Gworek, et al.; "Pressure dependence of Cu, Ag, and Fe/n-GaAs Schottky barrier heights"; Phy. Rev.B; Vol. 64; pp. 045322-1 – 6; (2001)
9. Peter Van Vessem et al.; "Rediscovering the Strain Gauge Pressure Sensor"; Sensors; 8 pps.; (1999);
10. Adhesives List printed from www.tokyosokki.co.jp/e/product...; on 6/27/2003;
11. Fujidura Semiconductor Pressure Sensors printed from www.fujidura.co.jp/sensor/press/intro... on 6/27/2003; and
12. Y. Ohmura; "Piezoresistance Effect in p-Type Semiconductors Si and Ge"; 21st International Conference on The Physics of Semiconductors; Vol. 1; pp. 273-76; (1992).

Applicants are submitting copies of the above-cited references.

Inasmuch as this Information Disclosure Statement is being submitted in accordance with the schedule set out in 37 C.F.R. § 1.97(b), no statement or fee is required.

Respectfully submitted,

Paul J. Esatto, Jr.
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INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				Docket Number (Optional) 16791 (03006)		Application Number Unassigned		
				Applicant(s) Alistair C.H. Rowe, et al.				
				Filing Date Herewith		Group Art Unit Unassigned		
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
FOREIGN PATENT DOCUMENTS								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)								
		Adhesives List printed from www.tokyosokki.co.jp/e/product... on 6/27/2003						
		Fujidura Semiconductor Pressure Sensors printed from www.fujidura.co.jp/sensor/press/intro... on 6/27/2003						
		Y. Ohmura; "Piezoresistance Effect in p-Type Semiconductors Si and Ge"; 21 st International Conference on The Physics of Semiconductors; Vol. 1; pp. 273-76; (1992)						
EXAMINER				DATE CONSIDERED				